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STGW39NC60VD

40 A - 600 V - very fast IGBT

Features

- Low C_{RES} / C_{IES} ratio (no cross conduction susceptibility)
- IGBT co-packaged with ultra fast free-wheeling diode

Applications

- High frequency inverters
- UPS
- Motor drivers
- Induction heating

Description

This IGBT utilizes the advanced PowerMESH[™] process resulting in an excellent trade-off between switching performance and low on-state behavior.

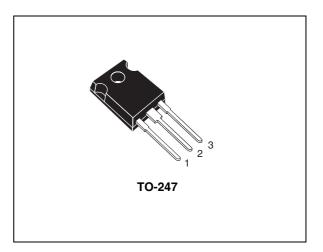


Figure 1. Internal schematic diagram

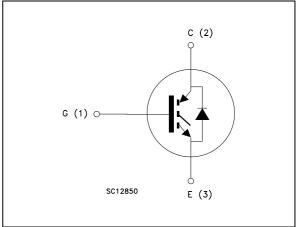


Table 1.Device summary

Order code	Marking	Package	Packaging
STGW39NC60VD	STGW39NC60VD GW39NC60VD		Tube

Contents

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Electrical ratings

Table 2. Absolute maximum ratings	Table 2.	Absolute	maximum	ratings
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Symbol	Parameter	Value	Unit
V _{CES}	Collector-emitter voltage ($V_{GE} = 0$)	600	V
۱ _C ⁽¹⁾	Collector current (continuous) at 25 °C	80	А
$I_{C}^{(1)}$	Collector current (continuous) at 100 °C	40	А
I _{CL} ⁽²⁾	Turn-off latching current	220	Α
I _{CP} ⁽³⁾	Pulsed collector current	220	А
V_{GE}	Gate-emitter voltage	± 20	V
١ _F	Diode RMS forward current at $T_C = 25 \ ^{\circ}C$	30	Α
I _{FSM}	Surge non repetitive forward current (tp=10 ms sinusoidal)	120	А
P _{TOT}	Total dissipation at $T_C = 25 \ ^{\circ}C$	250	W
Тj	Operating junction temperature	– 55 to 150	°C

1. Calculated according to the iterative formula:

$$I_{C}(T_{C}) = \frac{T_{JMAX}^{-T}C}{R_{THJ-C} \times V_{CESAT(MAX)}^{-T}(T_{C}, I_{C})}$$

2. Vclamp = 80%(V_{CES}) , Tj = 150 °C, R_G = 10 $\Omega,$ V_{GE}= 15 V

3. Pulse width limited by max. junction temperature allowed

Table 3. Thermal resistance

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case (IGBT) max	0.5	°C/W
R _{thj-case}	Thermal resistance junction-case (diode) max	1.5	°C/W
R _{thj-amb}	Thermal resistance junction-ambient max	50	°C/W



2 Electrical characteristics

(T_{CASE}=25 °C unless otherwise specified)

	Otatic					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)CES}	Collector-emitter breakdown voltage (V _{GE} = 0)	I _C = 1 mA	600			۷
V _{CE(sat)}	Collector-emitter saturation voltage	V _{GE} = 15 V, I _C = 30 A V _{GE} = 15 V, I _C = 30 A, T _C =125 °C		1.8 1.7	2.4	V V
V _{GE(th)}	Gate threshold voltage	$V_{CE} = V_{GE}, I_C = 1 \text{ mA}$	3.75		5.75	V
I _{CES}	Collector cut-off current $(V_{GE} = 0)$	V _{CE} = 600 V V _{CE} = 600 V, T _C = 125 °C			500 5	μA mA
I _{GES}	Gate-emitter leakage current (V _{CE} = 0)	V _{GE} = ± 20 V			±100	nA
9 _{fs} ⁽¹⁾	Forward transconductance	$V_{CE} = 15 V_{,} I_{C} = 30 A$		20		S

Table 4. Static

1. Pulsed: pulse duration = 300 μ s, duty cycle 1.5%

	Bynamie					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{ies} C _{oes} C _{res}	Input capacitance Output capacitance Reverse transfer capacitance	V _{CE} = 25 V, f = 1 MHz, V _{GE} = 0		2900 298 59		pF pF pF
Q _g Q _{ge} Q _{gc}	Total gate charge Gate-emitter charge Gate-collector charge	V_{CE} = 390 V, I _C = 30 A, V_{GE} = 15 V (see Figure 19)		126 16 46		nC nC nC

Table 5. Dynamic



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r (di/dt) _{onf}	Turn-on delay time Current rise time Turn-on current slope	$V_{CC} = 390 \text{ V}, \text{ I}_{C} = 30 \text{ A},$ $R_{G} = 10 \Omega, \text{ V}_{GE} = 15 \text{ V}$ (see Figure 18)		33 13 2500		ns ns A/µs
t _{d(on)} t _r (di/dt) _{on}	Turn-on delay time Current rise time Turn-on current slope	$V_{CC} = 390 \text{ V}, I_C = 30 \text{ A},$ $R_G = 10\Omega, V_{GE} = 15 \text{ V}$ $T_C = 125 \text{ °C}$ <i>(see Figure 18)</i>		32 14 2280		ns ns A/µs
t _{r(Voff)} t _{d(off)} t _f	Off voltage rise time Turn-off delay time Current fall time	$V_{CC} = 390 \text{ V}, \text{ I}_{C} = 30 \text{ A},$ $R_{G} = 10 \Omega, V_{GE} = 15 \text{ V}$ (see Figure 18)		33 178 65		ns ns ns
t _{r(Voff)} t _{d(off)} t _f	Off voltage rise time Turn-off delay time Current fall time	$V_{CC} = 390 \text{ V}, \text{ I}_{C} = 30 \text{ A},$ $R_{G}=10 \Omega, V_{GE}=15 \text{ V}$ $T_{C}=125 \text{ °C}$ <i>(see Figure 18)</i>		68 238 128		ns ns ns

Table 6. Switching on/off (inductive load)

Table 7. Switching energy (inductive load)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
E _{on} ⁽¹⁾ E _{off} ⁽²⁾ E _{ts}	Turn-on switching losses Turn-off switching losses Total switching losses	$V_{CC} = 390 \text{ V}, I_C = 30 \text{ A}$ $R_G = 10 \Omega, V_{GE} = 15 \text{ V},$ <i>(see Figure 20)</i>		333 537 870		μJ μJ μJ
$\begin{matrix} E_{\mathrm{on}}^{(1)} \\ E_{\mathrm{off}}^{(2)} \\ E_{\mathrm{ts}} \end{matrix}$	Turn-on switching losses Turn-off switching losses Total switching losses	$V_{CC} = 390 \text{ V}, I_C = 30 \text{ A}$ $R_G = 10 \Omega, V_{GE} = 15 \text{ V},$ $T_C = 125 \text{ °C}$ <i>(see Figure 20)</i>		618 1125 1743		μJ μJ μJ

 Eon is the turn-on losses when a typical diode is used in the test circuit in figure 2 Eon include diode recovery energy. If the IGBT is offered in a package with a co-pak diode, the co-pack diode is used as external diode. IGBTs & Diode are at the same temperature (25°C and 125°C)

2. Turn-off losses include also the tail of the collector current



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _F	Forward on-voltage	I _F = 30 A I _F = 30 A, T _C = 125 °C		2.4 1.8		V V
t _{rr} Q _{rr} I _{rrm}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _F = 30 A, V _R = 50 V, di/dt =100 A/µs <i>(see Figure 21)</i>		45 56 2.55		ns nC A
t _{rr} Q _{rr} I _{rrm}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_F = 30 \text{ A}, V_R = 50 \text{ V},$ $T_C = 125 \text{ °C},$ $di/dt = 100 \text{ A}/\mu\text{s}$ (see Figure 21)		100 290 5.8		ns nC A

 Table 8.
 Collector-emitter diode



2.1 Electrical characteristics (curves)

Figure 2. Output characteristics

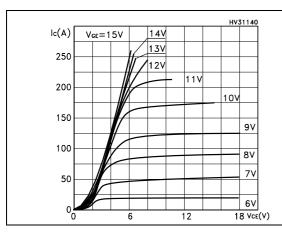


Figure 4. Transconductance

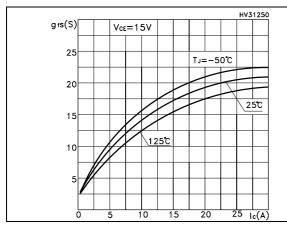
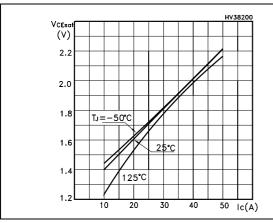


Figure 6. Collector-emitter on voltage vs collector current





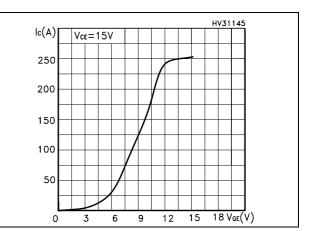


Figure 5. Collector-emitter on voltage vs temperature

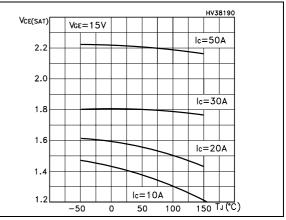
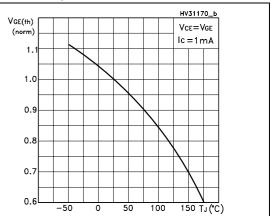
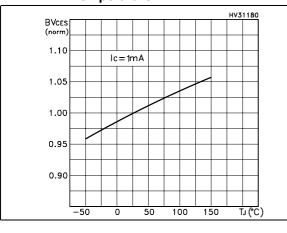
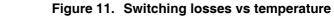


Figure 7. Normalized gate threshold vs temperature









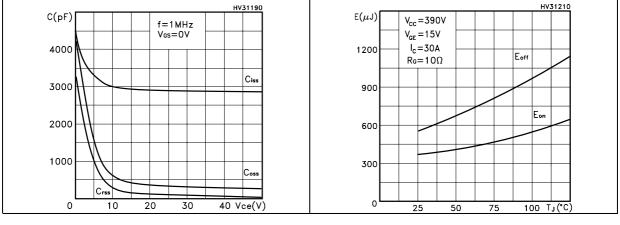
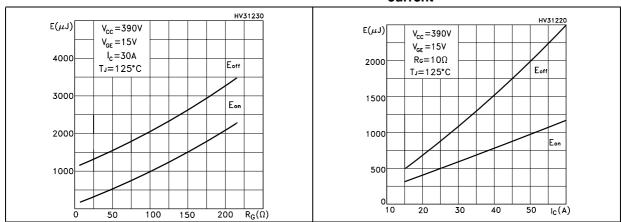
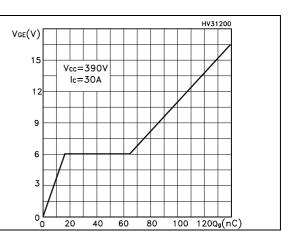


Figure 12. Switching losses vs gate resistance Figure 13. Switching losses vs collector current



e vs Figure 9. Gate charge vs gate-emitter voltage



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10²

10³ ۷_{СF}(۷)

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Figure 14. Thermal impedance

Figure 15. Turn-off SOA

 $I_{c}(A)$

10²

10

10

10

 10^{-2}

10⁻¹

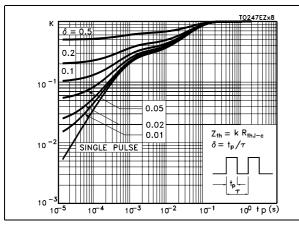
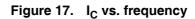
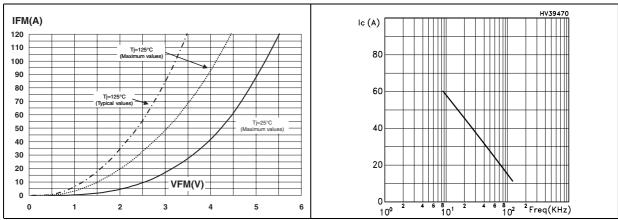


Figure 16. Emitter-collector diode characteristics



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2.2 Frequency applications

For a fast IGBT suitable for high frequency applications, the typical collector current vs. maximum operating frequency curve is reported. That frequency is defined as follows:

 $f_{MAX} = (P_D - P_C) / (E_{ON} + E_{OFF})$

• The maximum power dissipation is limited by maximum junction to case thermal resistance:

Equation 1

 $P_D = \Delta T / R_{THJ-C}$

considering $\Delta T = T_J - T_C = 125 \ ^\circ C - 75 \ ^\circ C = 50 \ ^\circ C$

• The conduction losses are:



Equation 2

 $\mathsf{P}_{\mathsf{C}} = \mathsf{I}_{\mathsf{C}} * \mathsf{V}_{\mathsf{CE}(\mathsf{SAT})} * \delta$

with 50% of duty cycle, $V_{\mbox{CESAT}}$ typical value @125 $^{\circ}\mbox{C}.$

• Power dissipation during ON & OFF commutations is due to the switching frequency:

Equation 3

 P_{SW} = (E_{ON} + E_{OFF}) * freq.Typical values @ 125 °C for switching losses are used (test conditions: V_{CE} = 390 V, V_{GE} = 15 V, R_G = 10 Ω). Furthermore, diode recovery energy is included in the E_{ON} (see note 2), while the tail of the collector current is included in the E_{OFF} measurements (see note 3).



3 Test circuit

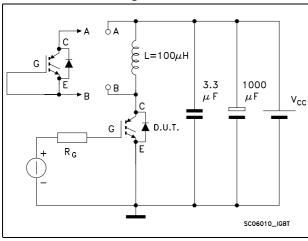


Figure 18. Test circuit for inductive load switching



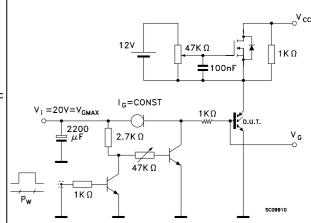
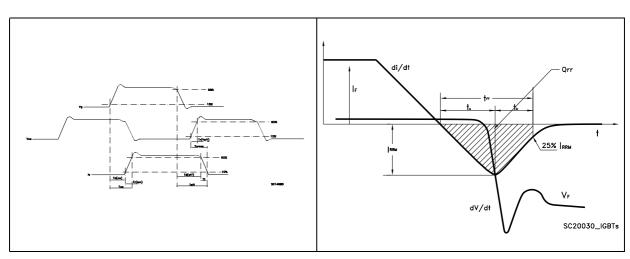


Figure 19. Gate charge test circuit





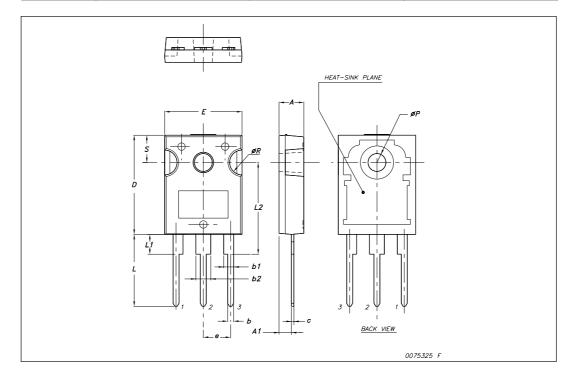
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: *www.st.com*



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	TO-247 mechanical data				
Dim.		mm.			
	Min.	Тур	Max .		
А	4.85		5.15		
A1	2.20		2.60		
b	1.0		1.40		
b1	2.0		2.40		
b2	3.0		3.40		
с	0.40		0.80		
D	19.85		20.15		
E	15.45		15.75		
е		5.45			
L	14.20		14.80		
L1	3.70		4.30		
L2		18.50			
øP	3.55		3.65		
øR	4.50		5.50		
S		5.50			



5 Revision history

Table 9.	Document revision history
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Date	Revision	Changes
17-Nov-2005	1	First release
05-May-2006	2	Inserted curves
10-Jul-2006	3	Modified value on Absolute maximum ratings
01-Dec-2006	4	Modified value on <i>Dynamic</i>
16-May-2007	5	New curves updated: Figure 5 and Figure 6
22-Aug-2007	6	Added new Figure 17 and new section 2.2: Frequency applications
31-Jan-2008	7	Modified: Table 8: Collector-emitter diode
29-Jul-2008	8	Updated V _{CE(sat)} on <i>Table 4</i>

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